

Search Notes

Application/Control No.

10/527,669

Examiner

John A. Tweel, Jr.

Applicant(s)/Patent under
Reexamination

IGAMI ET AL.

Art Unit

2612

SEARCHED

Class	Subclass	Date	Examiner
340	689	9/25/2006	JAT
	686.1	9/25/2006	JAT
	691.1	9/25/2006	JAT
200	61.45R	9/25/2006	JAT
	61.52	9/25/2006	JAT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR